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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Number : 10/707,657 Confirmation No.: 1656
Applicant : James Kenneth Aragones
Filed : December 30, 2003
Title : SYSTEM AND METHOD FOR MEASURING QUALITY OF
BASELINE MODELING TECHNIQUES
TC/Art Unit : 2123
Examiner: : Unknown

Docket No. : 61765.005012
Customer No. : 21967

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, and in compliance with the duty of disclosure set forth in 37 C.F.R. § 1.56, applicant is submitting herewith the attached Form PTO-SB/08A listing references for consideration and to be made of record herein by the U.S. Patent and Trademark Office in the above-captioned application. Copies of the listed references are being submitted herewith.

Consideration of the foregoing plus the prompt return of a copy of the enclosed Form SB/08A with the Examiner's initials in the left column in accordance with MPEP 609 are respectfully requested.

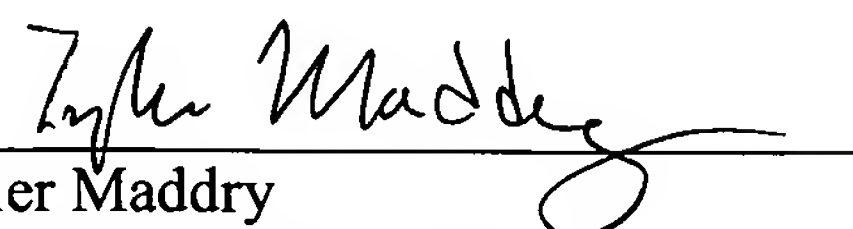
In accordance with 37 C.F.R. § 1.97(b), this Information Disclosure Statement is being submitted before a first Office Action. Therefore, it is respectfully submitted that no fee is required for consideration of this information. However, in the event any fee is deemed necessary, the Commissioner is authorized to charge the undersigned's Deposit Account No. 50-0206.

Respectfully submitted,

HUNTON & WILLIAMS LLP

Dated: June 23, 2004

By:


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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT***(use as many sheets as necessary)*

Application Number	10/707,657
Filing Date	12/30/2003
First Named Inventor	James Kenneth Aragones
Art Unit	2123
Confirmation No.	1656
Examiner Name	Unknown

Sheet	1	of	1	Attorney Docket Number	61765.005012
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U.S. PATENT DOCUMENTS

*Examiner Initials	Cite No.	DOCUMENT NUMBER Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	6,067,486	05-23-2000	Aragones et al.	
	2	6,473,677	10-29-2002	Hershey et al.	
	3	2003/0036891	02-20-2003	Aragones et al.	
	4	10/707,655		Aragones	
	5	10/707,656		Aragones	

FOREIGN PATENT DOCUMENTS

*Examiner Initial	Cite No.	FOREIGN PATENT DOCUMENT		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	TRANSLATION	
		Country Code:	Number - Kind Code (if known)				YES	NO
	6	EP	1146468	10-17-2001	Aragones et al.			
	7	EP	1160712	12-05-2001	Aragones			

OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS

*Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	TRANSLATION
	8	"Multiple Regression," http://www2.chass.ncsu.edu/garson/pa765/regress.htm , pp. 1-27 (printed 10/22/03).	
	9	"Introduction to Regression Analysis," http://www.nlreg.com/intro.htm , pp. 1-3 (printed 10/22/03).	

EXAMINER SIGNATURE

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.